Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/705,947	LEE ET AL.
Examiner	Art Unit
Benjamin E. Lanier	2132

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Limited Search of 713/151 726/11-14 See Attachment	12/18/200	
East Search See Attachment	12/18/200	6 H
Inspec Search See Attachment	12/18/200	6 K
Inventor Name Search Palm	12/18/200	6 He